

Analysis and Design of Analog Integrated Circuits
Lecture 6

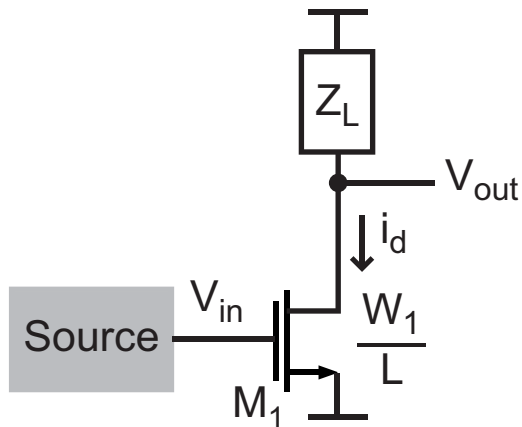
Current Mirrors

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February 8, 2012

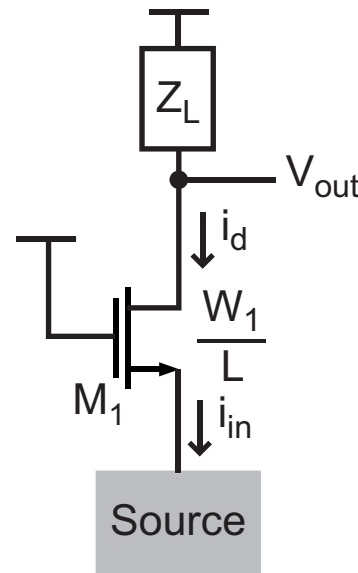
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From Lecture 5: Basic Single-Stage CMOS Amplifiers

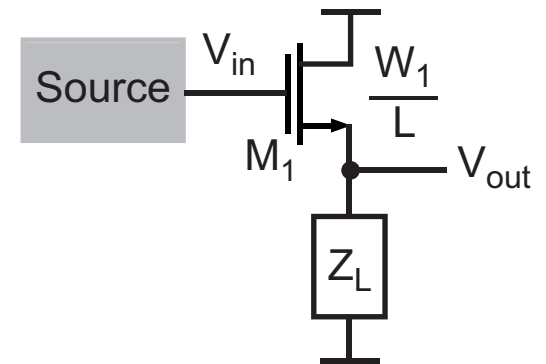
Common Source



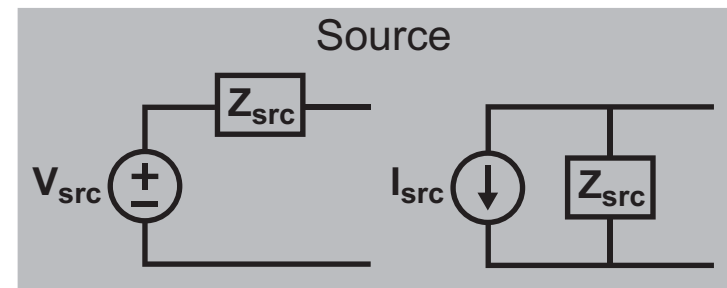
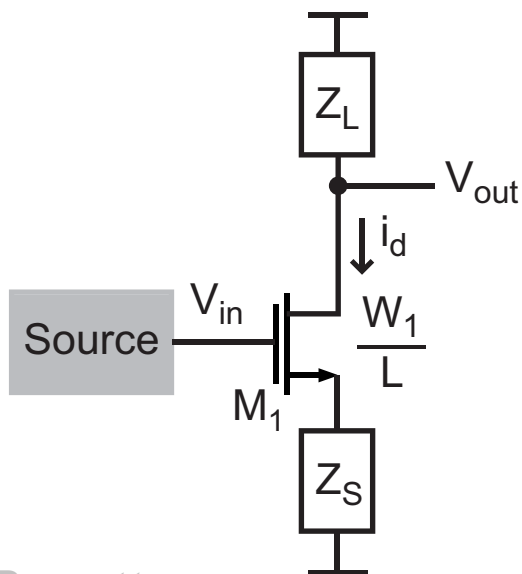
Common Gate



Source Follower

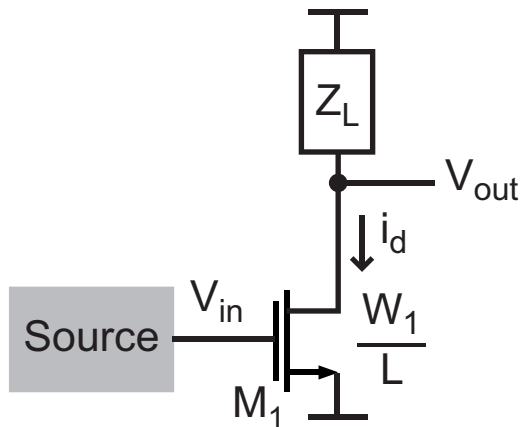


Common Source with Source Degeneration

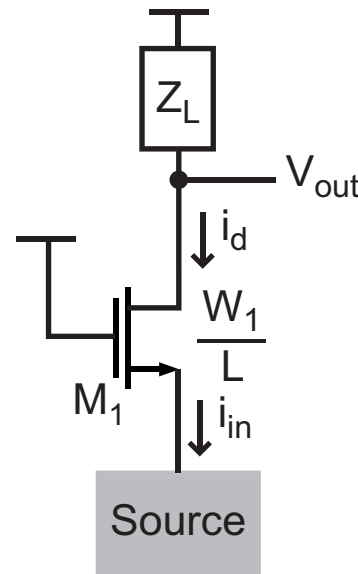


A Closer Look at Load Impedance

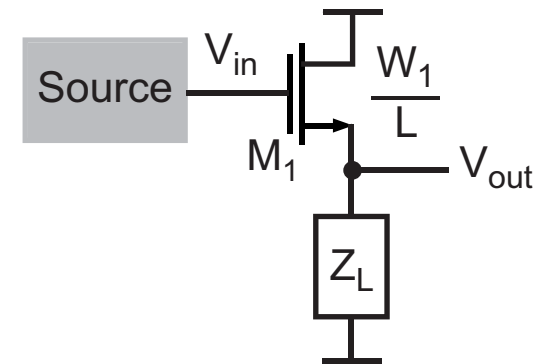
Common Source



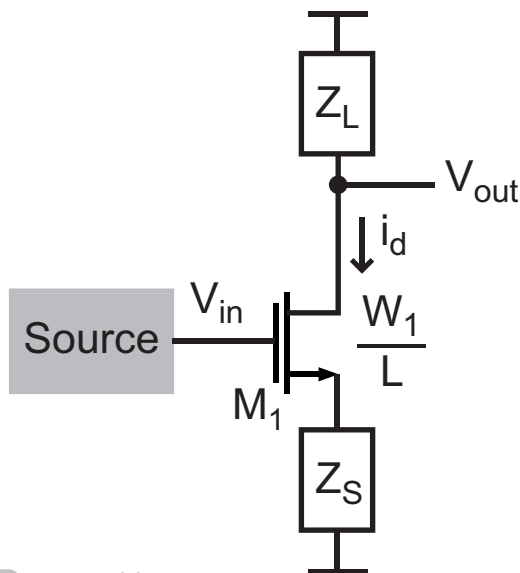
Common Gate



Source Follower

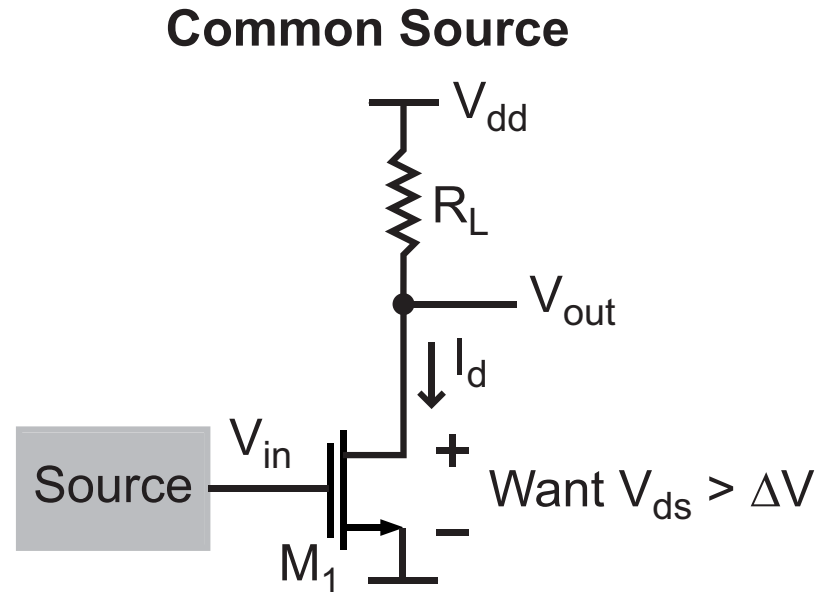


Common Source with Source Degeneration



- To achieve high gain (or low attenuation in the case of a source follower), it is very desirable to achieve high load impedance, Z_L
 - Unfortunately, using a simple resistor of high value has issues
 - What are these issues?

Issue #1: Headroom Limitations



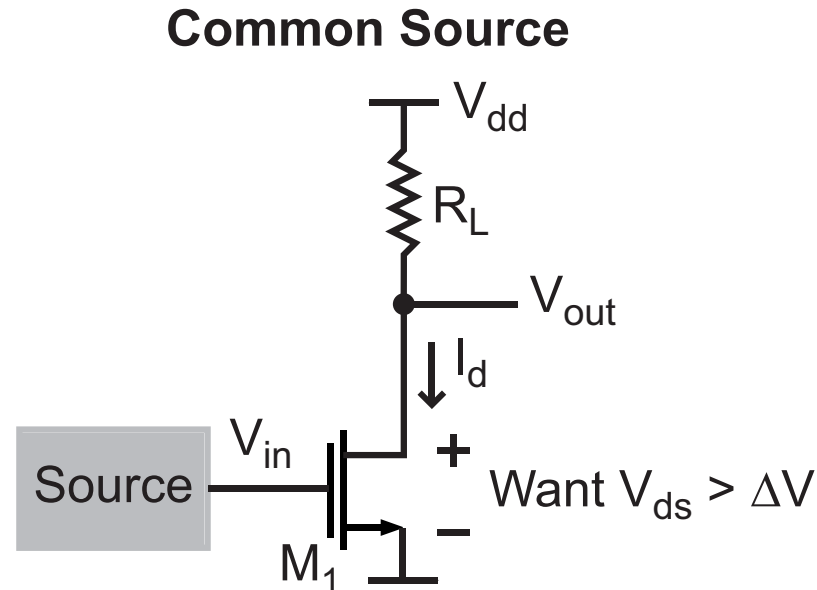
- The bias current of the device is a direct function of R_L

$$I_d = \frac{V_{dd} - V_{ds}}{R_L}$$

- V_{dd} is $< 3.6V$ for most modern CMOS processes
- V_{ds} must be greater than ΔV to maintain device saturation

**Large R_L implies small I_d
(implies small g_m , poor frequency response, etc.)**

Issue #2: Area of Circuit

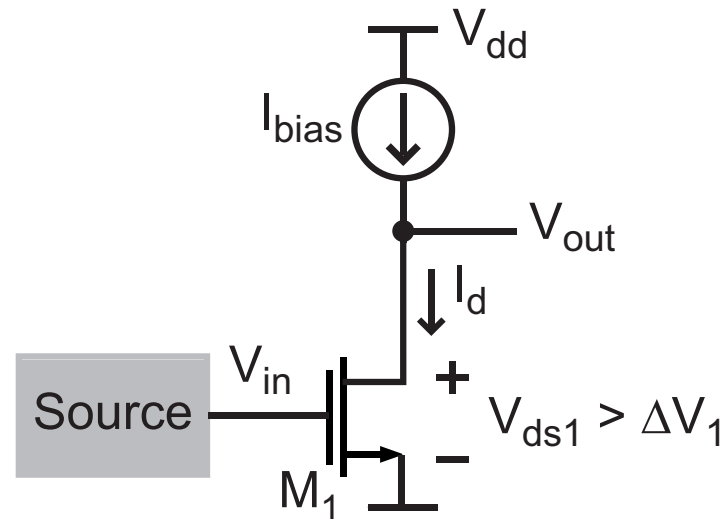


- The most common resistors for precision analog circuits are often based on unsilicided polysilicon layers
 - The sheet resistance of unsilicided polysilicon is often $< 1\text{k}\Omega/\text{square}$

Large polysilicon R_L implies relatively large circuit area
(implies high relative cost)

An Elegant Approach to Achieving High Gain

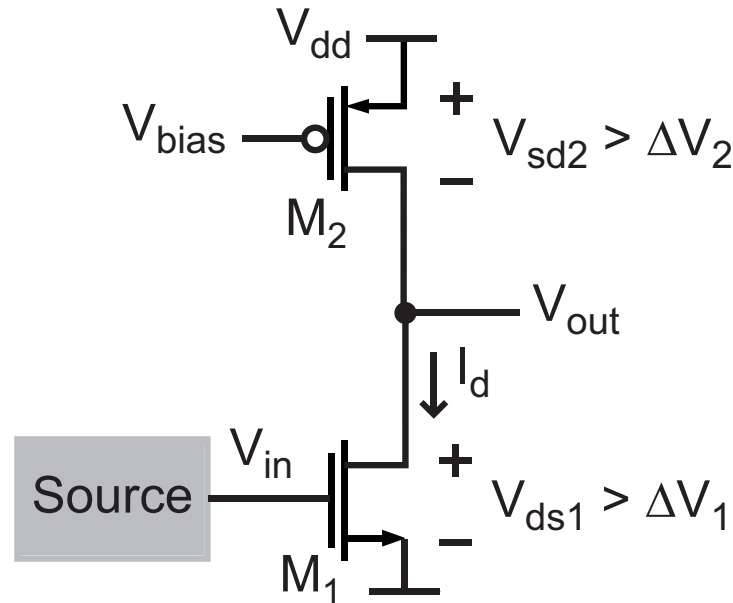
Common Source



- Replacement of resistor load with a current source yields the highest possible DC gain out of the amplifier
 - Current source determines I_d of device
- We can make current sources out of transistors
 - Generally smaller area than polysilicon resistors

What is the small signal gain of the above circuit?

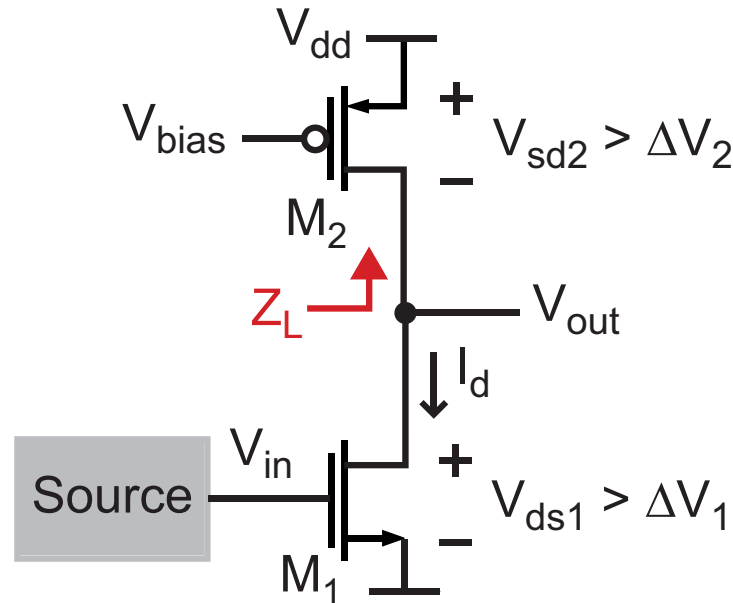
A Simple Transistor Based Current Source



- **Simply use a PMOS load that is properly biased**
 - If we keep the PMOS in saturation, its current is relatively constant despite V_{sd} variations
 - This is the desired behavior of a current source

What are the nonideal issues of the above approach?

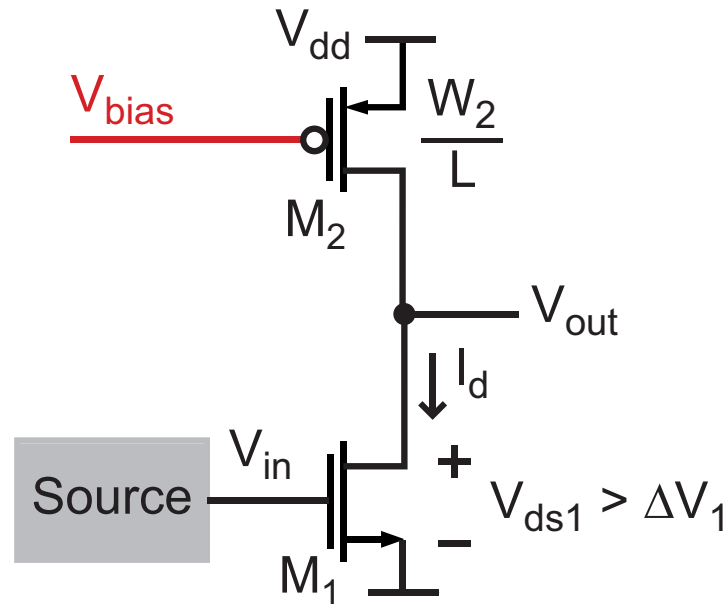
Issue #1: Impedance of PMOS Device



- An ideal current source has infinite impedance
- PMOS devices have finite impedance
 - What is Z_L in the above circuit?
 - How does finite Z_L impact the gain of the circuit?

We will later examine techniques to increase Z_L

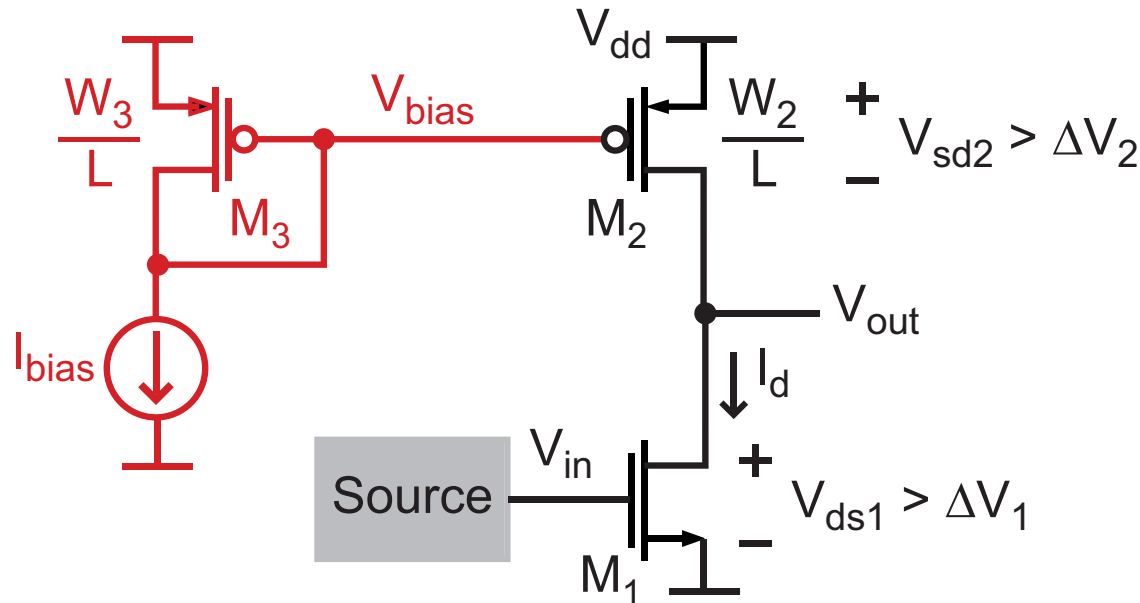
Issue #1: High Bias Sensitivity



- The PMOS device current, I_d , is very sensitive to the value of V_{bias}
 - We want I_d to be relatively constant across temperature and process variations

How can we achieve tighter control over I_d across temperature and process variations?

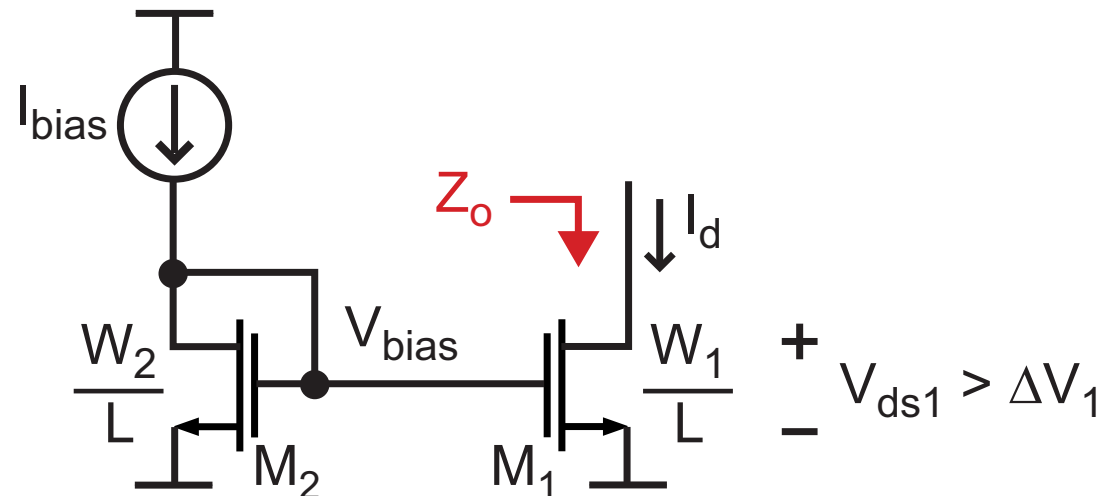
Key Technique: Use Current Mirror



- **Key idea: use a different PMOS device, M_3 , to transform a bias current, I_{bias} , into bias voltage, V_{bias}**
 - V_{bias} now yields a consistent current, I_d , in M_2 (assumed to be in saturation) across temperature and process variations
 - Note that layout of M_2 and M_3 must be done properly to achieve good device matching

How does I_d relate to I_{bias} ?

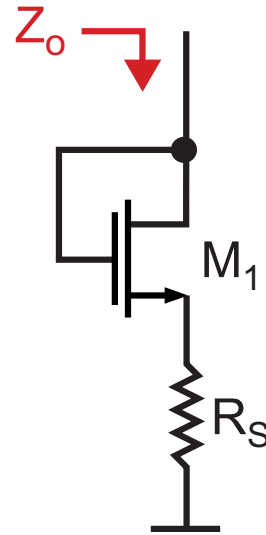
NMOS Devices Can Also Be Used for Current Mirrors



- We often use both NMOS and PMOS versions in designs
 - We'll explore this issue further later in the semester
- General issue: current mirrors involve direct feedback between drain and gate

Can we apply proposed Thevenin modeling approach to current mirrors?

Issue: Thevenin Impedances Are Not Adequate



- Looking as purely Thevenin impedances

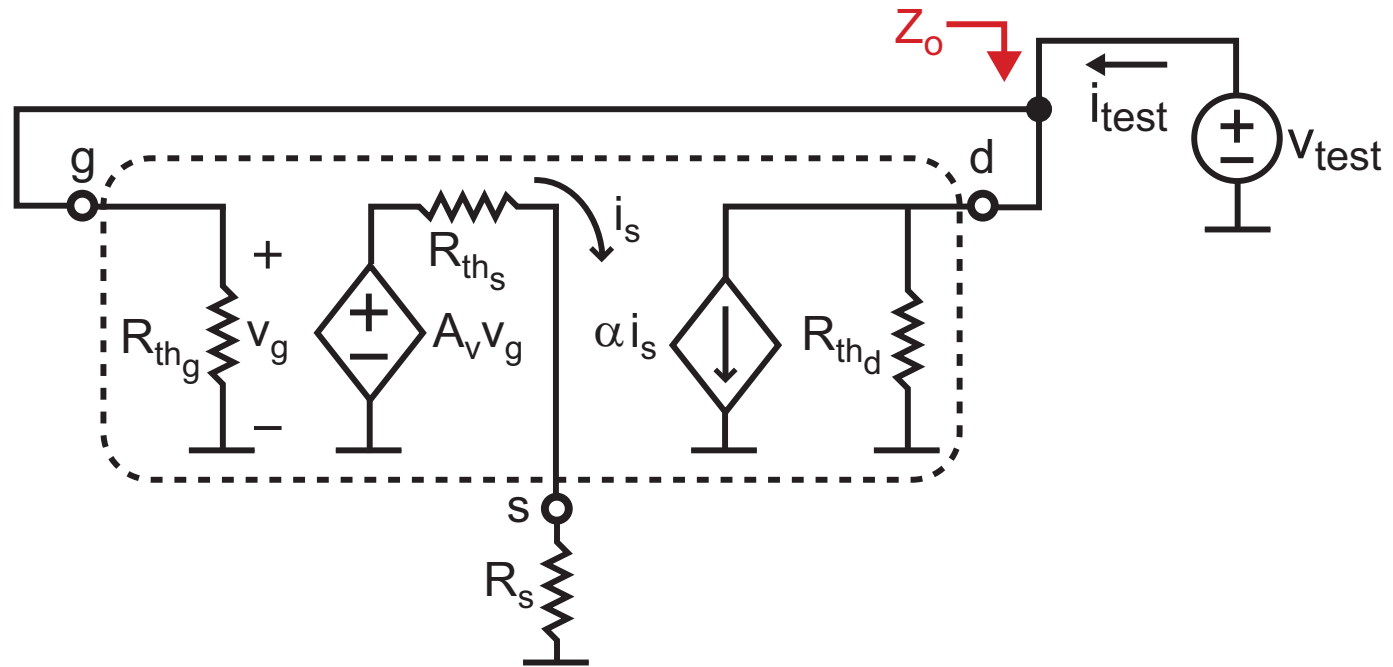
$$Z_o = R_{th_d} || R_{th_g} = r_o(1 + g_m R_s) || \infty = r_o(1 + g_m R_s)$$

- But, in reality

$$Z_o = \frac{1}{g_m} + \left(\frac{g_m + g_{mb}}{g_m} \right) R_s$$

- Issue: coupling between source, drain, or gate
 - Do we have to abandon the Thevenin method?

Try Proposed Thevenin Model



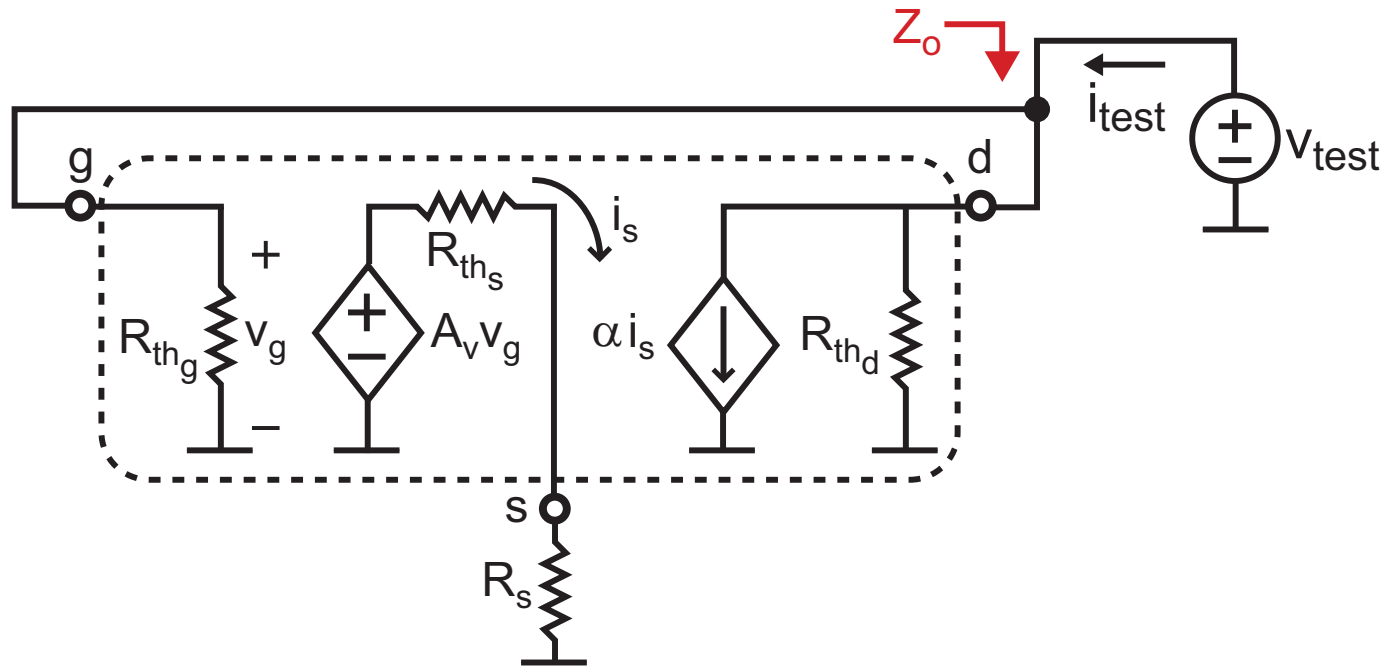
- **Key Calculations (ignore R_{th_d} for now):**

$$R_{th_g} = \infty, \quad R_{th_s} \approx \frac{1}{g_m + g_{mb}}, \quad A_v \approx \frac{g_m}{g_m + g_{mb}}, \quad \alpha = 1$$

$$\Rightarrow i_{test} = \alpha i_s = v_{test} A_v \frac{1}{R_{th_s} + R_s} = v_{test} \frac{g_m}{1 + R_s(g_m + g_{mb})}$$

$$\Rightarrow Z_o = \frac{v_t}{i_t} = \frac{1}{g_m} + \left(\frac{g_m + g_{mb}}{g_m} \right) R_s$$

Proposed Thevenin Model Works!



- Now include R_{thd} :

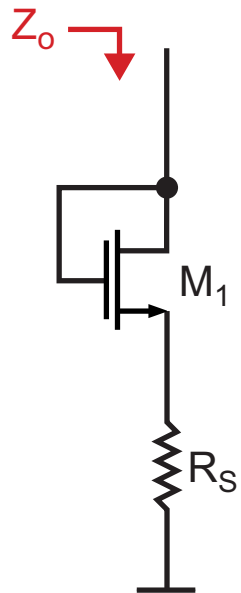
$$\Rightarrow Z_o = \left(\frac{1}{g_m} + \left(\frac{g_m + g_{mb}}{g_m} \right) R_s \right) \parallel R_{thd}$$

However: $R_{thd} = r_o(1 + g_m R_s) \gg \frac{1}{g_m} + \left(\frac{g_m + g_{mb}}{g_m} \right) R_s$ for $g_m r_o \gg 1$

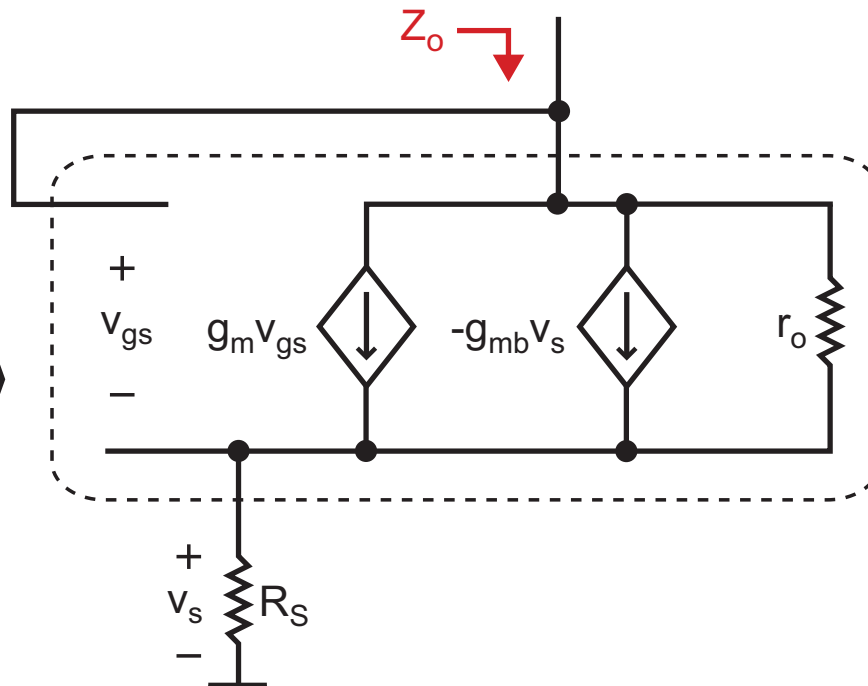
$$\Rightarrow Z_o = \frac{1}{g_m} + \left(\frac{g_m + g_{mb}}{g_m} \right) R_s$$

Check Thevenin Resistance Calculation

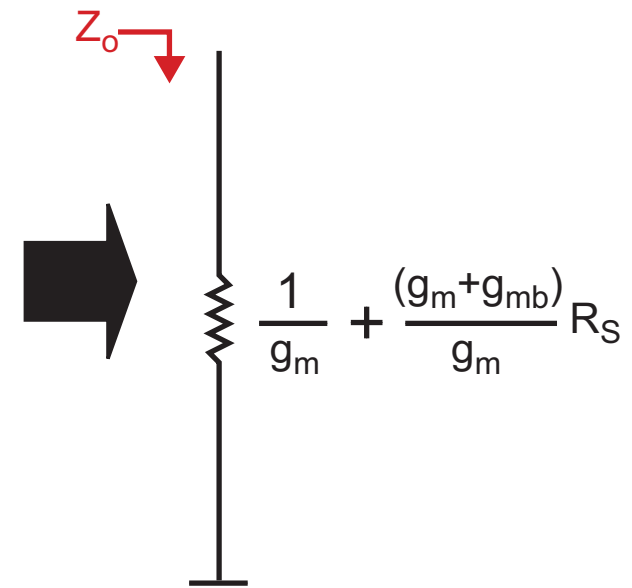
Diode-Connected Device



Derive Z_o Using Hybrid- π Model



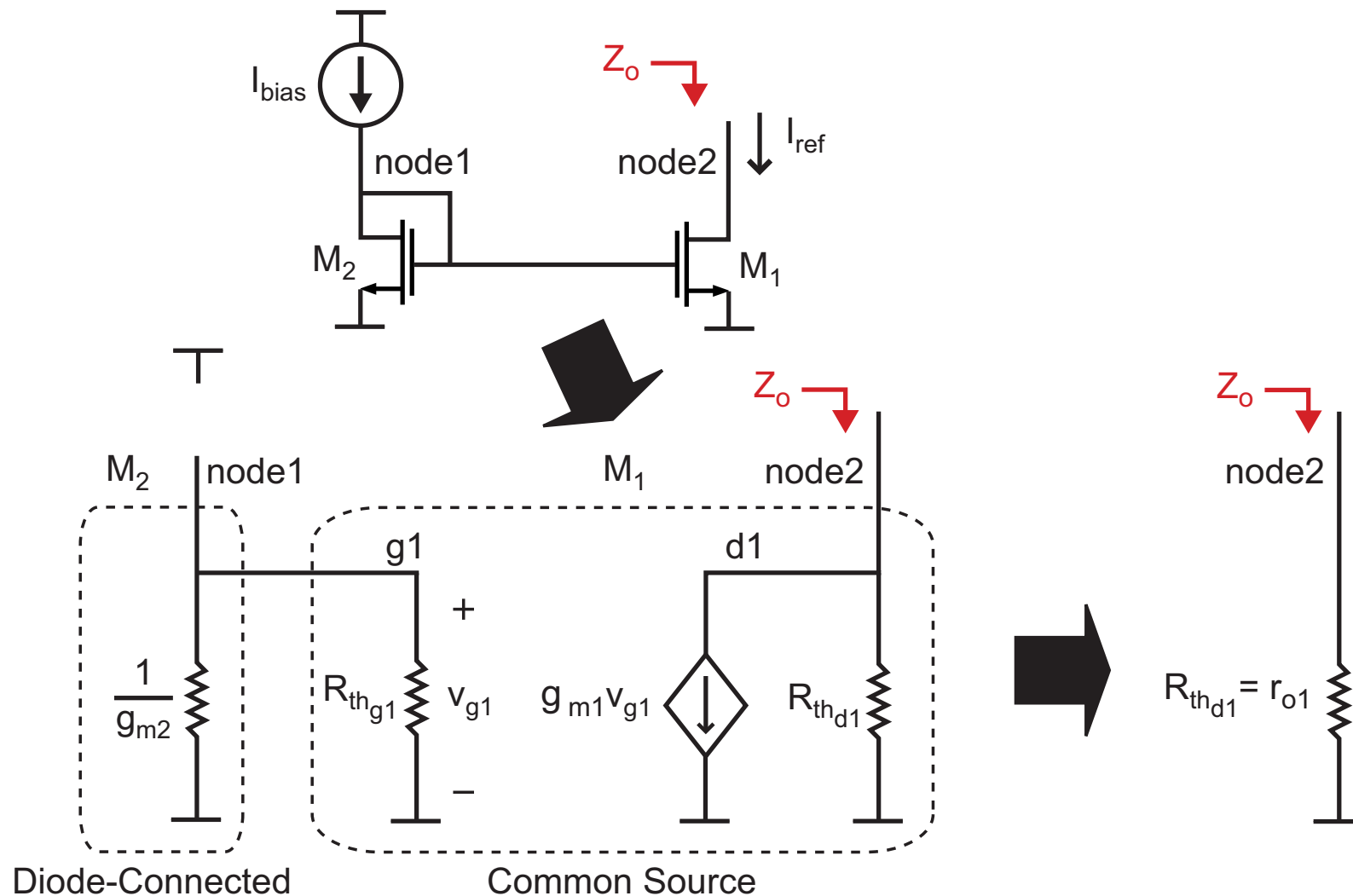
Resulting One-Port Model



- Plug in Hybrid- π to do the analysis
 - Answer agrees with proposed Thevenin model approach
- Easiest to just memorize this result:

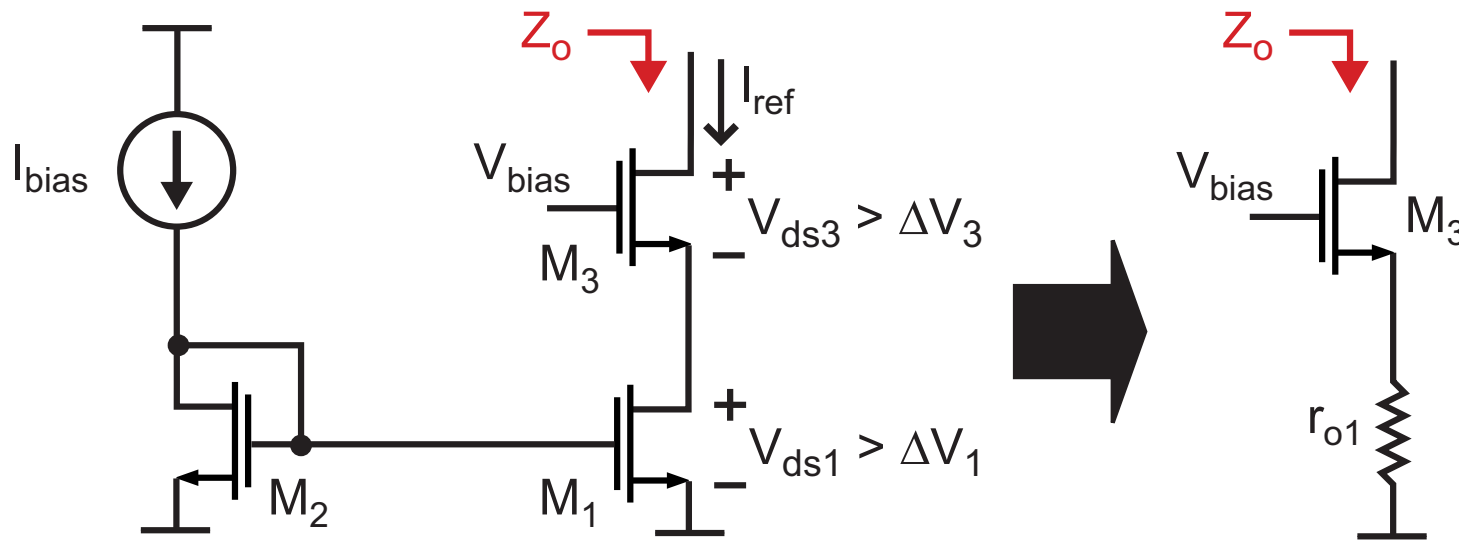
Diode connected MOS looks like a resistor of value $1/g_m$

Now Apply Thevenin Approach to the Current Mirror



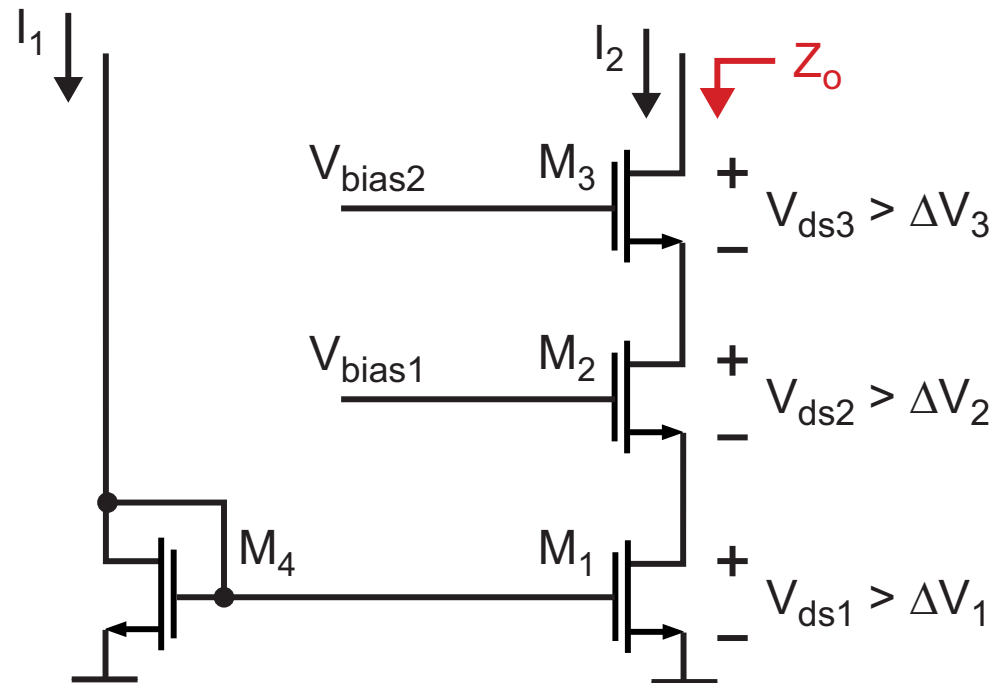
- **Key parameter of current source: output resistance**
 - Corresponds to r_o of device

Cascode Current Source



- Offers increased output resistance
 - Calculate using Thevenin resistance method
 - How does I_{ref} compare to I_{bias} ?

Double Cascode Current Source



- Offers *further* increased output resistance
 - Calculate using Thevenin resistance method
 - How does I_2 compare to I_1 ?